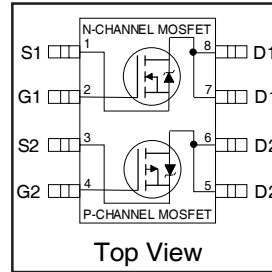


# IRF7309QPbF

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dual N and P Channel MOSFET
- Surface Mount
- Available in Tape & Reel
- 150°C Operating Temperature
- Lead-Free

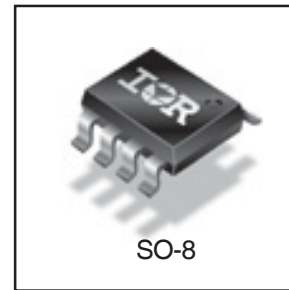


	N-Ch	P-Ch
$V_{DSS}$	30V	-30V
$R_{DS(on)}$	0.050Ω	0.10Ω

## Description

These HEXFET® Power MOSFET's in a Dual SO-8 package utilize the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of these HEXFET Power MOSFET's are a 150°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These benefits combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

The efficient SO-8 package provides enhanced thermal characteristics and dual MOSFET die capability making it ideal in a variety of power applications. This dual, surface mount SO-8 can dramatically reduce board space and is also available in Tape & Reel.



## Absolute Maximum Ratings

Parameter		Max.		Units
		N-Channel	P-Channel	
$I_D @ T_A = 25^\circ\text{C}$	10 Sec. Pulse Drain Current, $V_{GS} @ 10\text{V}$	4.7	-3.5	A
$I_D @ T_A = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	4.0	-3.0	A
$I_D @ T_A = 70^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	3.2	-2.4	A
$I_{DM}$	Pulsed Drain Current $\text{\textcircled{D}}$	16	-12	A
$P_D @ T_A = 25^\circ\text{C}$	Power Dissipation (PCB Mount)**	1.4		W
	Linear Derating Factor (PCB Mount)**	0.011		W/°C
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$		V
$dv/dt$	Peak Diode Recovery $dv/dt$ $\text{\textcircled{D}}$	6.9	-6.0	V/ns
$T_J, T_{STG}$	Junction and Storage Temperature Range	-55 to + 150		°C

## Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-Amb. (PCB Mount, steady state)**	—	—	90	°C/W

\*\* When mounted on 1" square PCB (FR-4 or G-10 Material).

For recommended footprint and soldering techniques refer to application note #AN-994.

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Parameter	Description		Min.	Typ.	Max.	Units	Conditions
			N-Ch	P-Ch	N-Ch		
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	N-Ch	30	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
		P-Ch	-30	—	—		V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	N-Ch	—	0.032	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
		P-Ch	—	-0.037	—		Reference to 25°C, I <sub>D</sub> = -1mA
R <sub>DS(ON)</sub>	Static Drain-to-Source On-Resistance	N-Ch	—	—	0.050	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 2.4A ③
			—	—	0.080		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 2.0A ③
		P-Ch	—	—	0.10		V <sub>GS</sub> = -10V, I <sub>D</sub> = -1.8A ③
			—	—	0.16		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -1.5A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	N-Ch	1.0	—	—	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
		P-Ch	-1.0	—	—		V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
g <sub>fs</sub>	Forward Transconductance	N-Ch	5.2	—	—	S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 2.4A ③
		P-Ch	2.5	—	—		V <sub>DS</sub> = -24V, I <sub>D</sub> = -1.8A ③
I <sub>DSS</sub>	Drain-to-Source Leakage Current	N-Ch	—	—	1.0	μA	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V
		P-Ch	—	—	-1.0		V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V
		N-Ch	—	—	25		V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
		P-Ch	—	—	-25		V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	N-P	—	—	±100	nA	V <sub>GS</sub> = ± 20V
Q <sub>g</sub>	Total Gate Charge	N-Ch	—	—	25	nC	N-Channel I <sub>D</sub> = 2.6A, V <sub>DS</sub> = 16V, V <sub>GS</sub> = 4.5V ③
		P-Ch	—	—	25		
Q <sub>gs</sub>	Gate-to-Source Charge	N-Ch	—	—	2.9	nC	P-Channel I <sub>D</sub> = -2.2A, V <sub>DS</sub> = -16V, V <sub>GS</sub> = -4.5V ③
		P-Ch	—	—	2.9		
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	N-Ch	—	—	7.9	nC	P-Channel I <sub>D</sub> = -2.2A, V <sub>DS</sub> = -16V, V <sub>GS</sub> = -4.5V ③
		P-Ch	—	—	9.0		
t <sub>d(on)</sub>	Turn-On Delay Time	N-Ch	—	6.8	—	ns	N-Channel V <sub>DD</sub> = 10V, I <sub>D</sub> = 2.6A, R <sub>G</sub> = 6.0Ω, R <sub>D</sub> = 3.8Ω ③
t <sub>r</sub>	Rise Time	N-Ch	—	21	—		
		P-Ch	—	17	—		
t <sub>d(off)</sub>	Turn-Off Delay Time	N-Ch	—	22	—		
		P-Ch	—	25	—		
t <sub>f</sub>	Fall Time	N-Ch	—	7.7	—		
		P-Ch	—	18	—		
L <sub>D</sub>	Internal Drain Inductance	N-P	—	4.0	—	nH	Between lead tip and center of die contact
L <sub>S</sub>	Internal Source Inductance	N-P	—	6.0	—		
C <sub>iss</sub>	Input Capacitance	N-Ch	—	520	—	pF	N-Channel V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1.0MHz ③
		P-Ch	—	440	—		
C <sub>oss</sub>	Output Capacitance	N-Ch	—	180	—		
		P-Ch	—	200	—		
C <sub>rss</sub>	Reverse Transfer Capacitance	N-Ch	—	72	—		
		P-Ch	—	93	—		

## Source-Drain Ratings and Characteristics

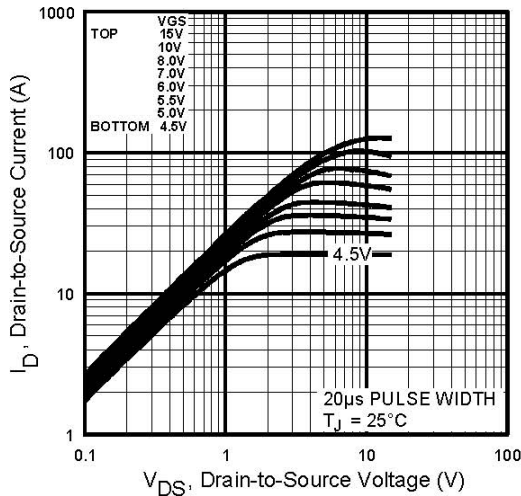
Parameter	Description		Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	N-Ch	—	—	1.8	A	
		P-Ch	—	—	-1.8		
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	N-Ch	—	—	16	A	
		P-Ch	—	—	-12		
V <sub>SD</sub>	Diode Forward Voltage	N-Ch	—	—	1.0	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 1.8A, V <sub>GS</sub> = 0V ③
		P-Ch	—	—	-1.0		T <sub>J</sub> = 25°C, I <sub>S</sub> = -1.8A, V <sub>GS</sub> = 0V ③
t <sub>rr</sub>	Reverse Recovery Time	N-Ch	—	47	71	ns	N-Channel T <sub>J</sub> = 25°C, I <sub>F</sub> = 2.6A, di/dt = 100A/μs
		P-Ch	—	53	80		
Q <sub>rr</sub>	Reverse Recovery Charge	N-Ch	—	56	84	nC	P-Channel T <sub>J</sub> = 25°C, I <sub>F</sub> = -2.2A, di/dt = 100A/μs ③
		P-Ch	—	66	99		
t <sub>on</sub>	Forward Turn-On Time	N-P	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 23 )

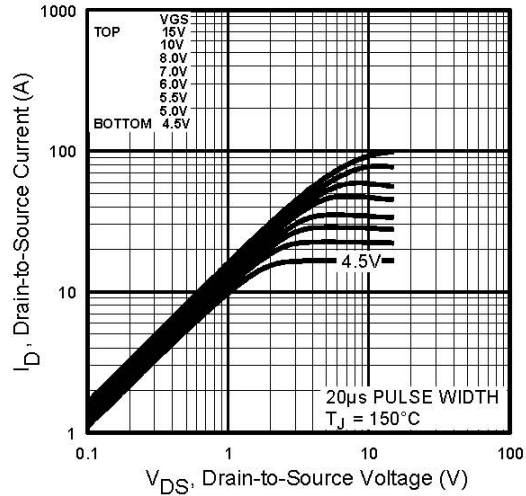
② N-Channel I<sub>SD</sub> ≤ 2.4A, di/dt ≤ 73A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 150°C  
P-Channel I<sub>SD</sub> ≤ -1.8A, di/dt ≤ 90A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 150°C

③ Pulse width ≤ 300μs; duty cycle ≤ 2%.

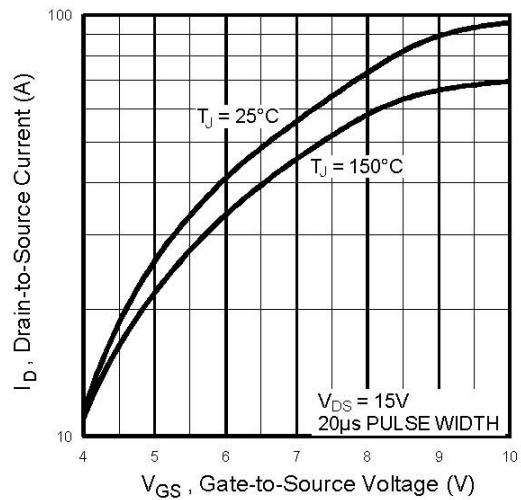
## N-Channel



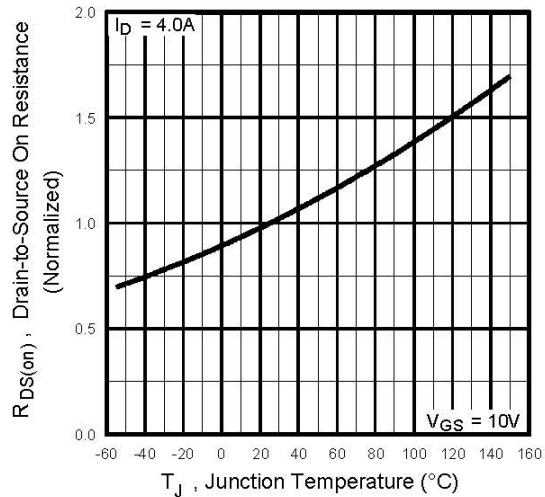
**Fig 1.** Typical Output Characteristics,  
 $T_J = 25^\circ\text{C}$



**Fig 2.** Typical Output Characteristics,  
 $T_J = 150^\circ\text{C}$

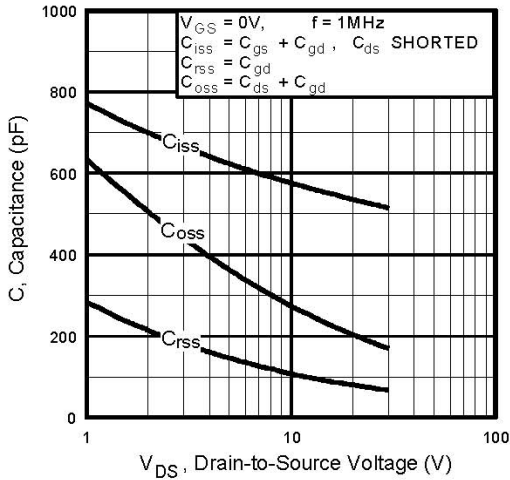


**Fig 3.** Typical Transfer Characteristics

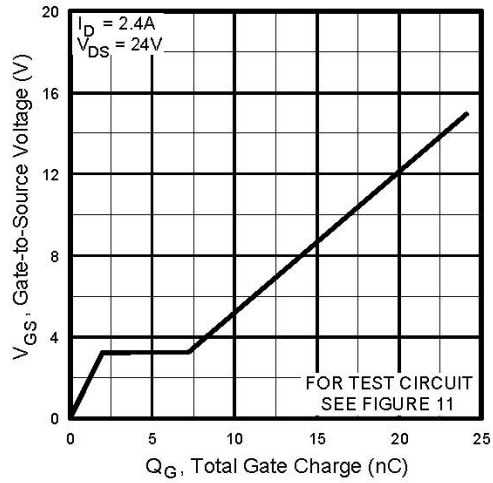


**Fig 4.** Normalized On-Resistance  
Vs. Temperature

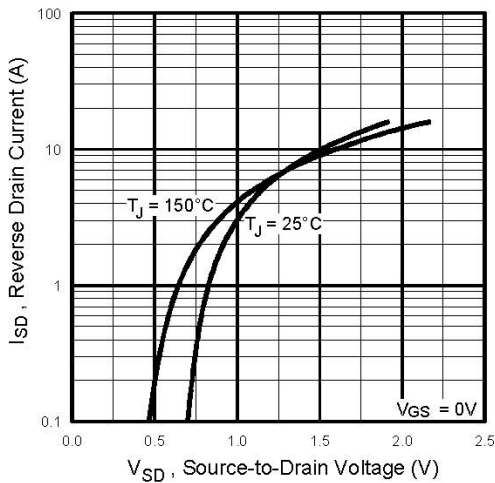
## N-Channel



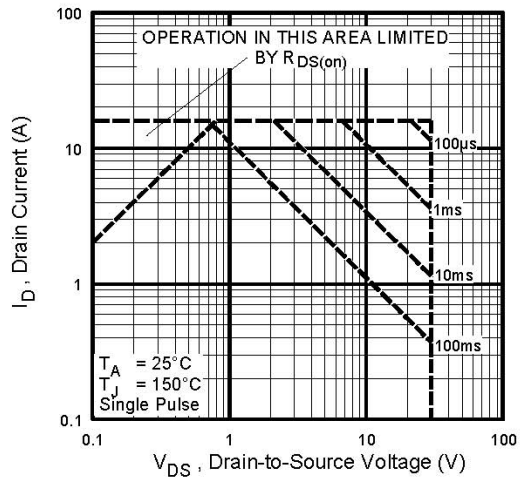
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

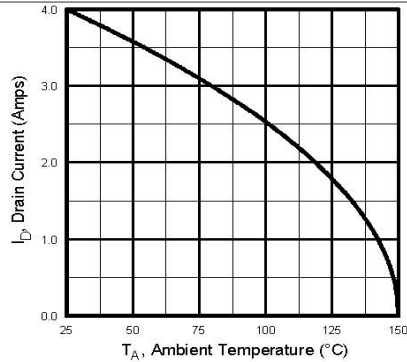


**Fig 7.** Typical Source-Drain Diode Forward Voltage

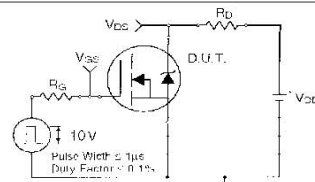


**Fig 8.** Maximum Safe Operating Area

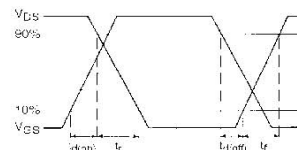
## N-Channel



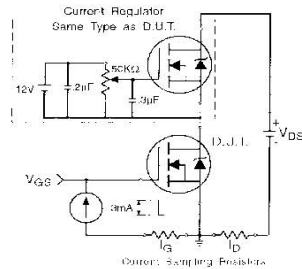
**Fig 9.** Max. Drain Current Vs. Ambient Temp.



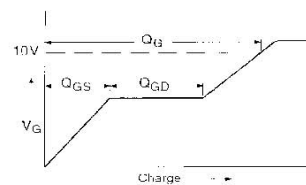
**Fig 10a.** Switching Time Test Circuit



**Fig 10b.** Switching Time Waveforms

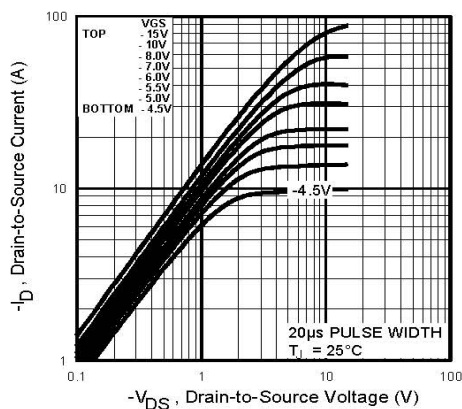


**Fig 11a.** Gate Charge Test Circuit

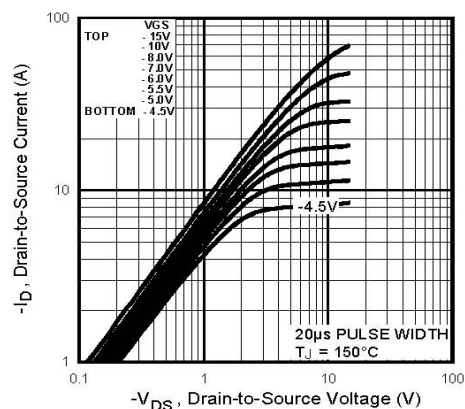


**Fig 11b.** Basic Gate Charge Waveform

## P-Channel

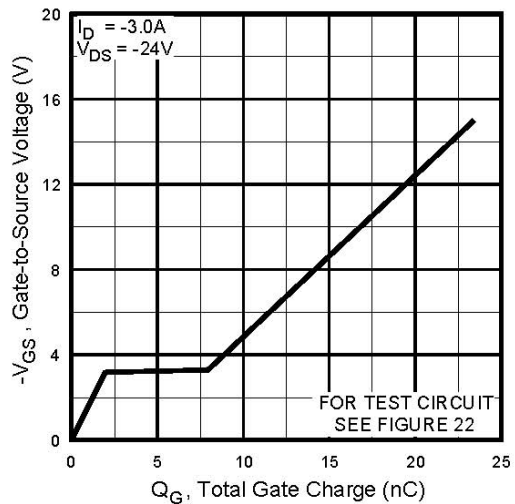
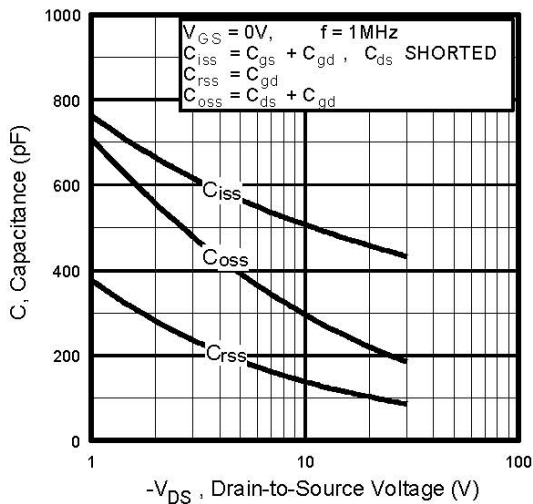
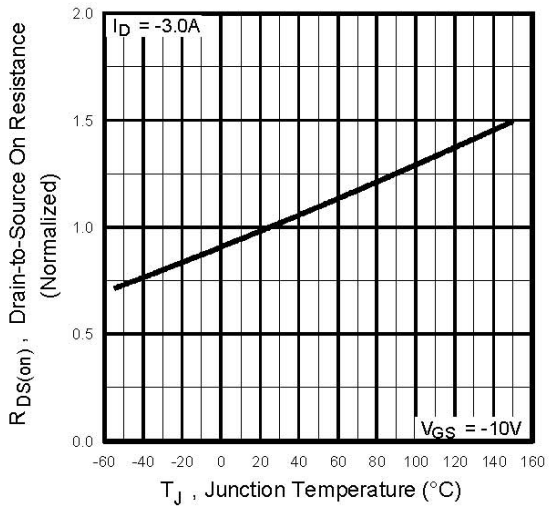
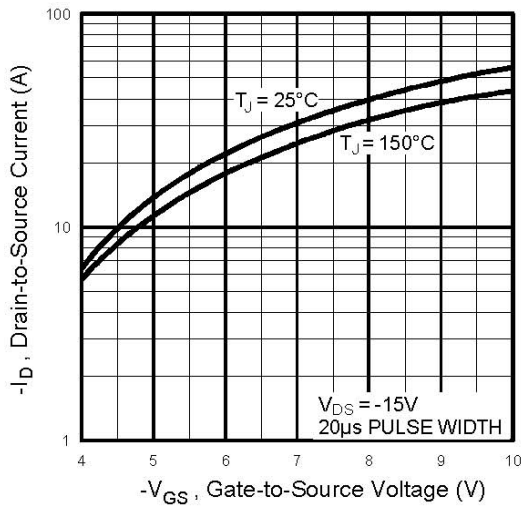


**Fig 12.** Typical Output Characteristics,  $T_J = 25^\circ\text{C}$



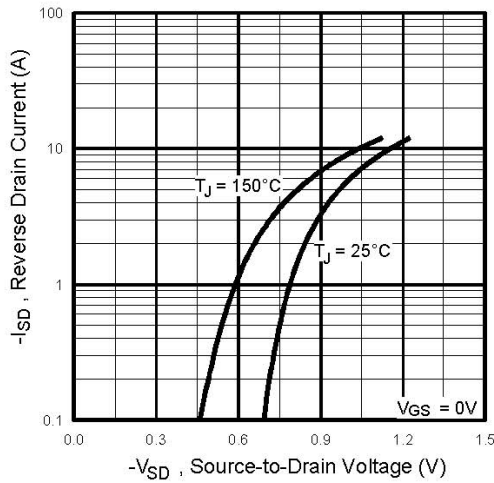
**Fig 13.** Typical Output Characteristics,  $T_J = 150^\circ\text{C}$

## P-Channel

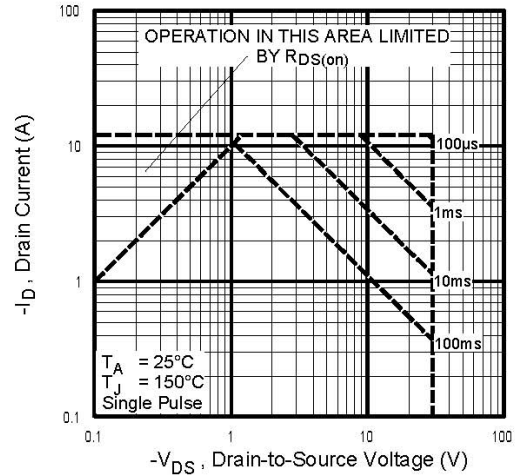




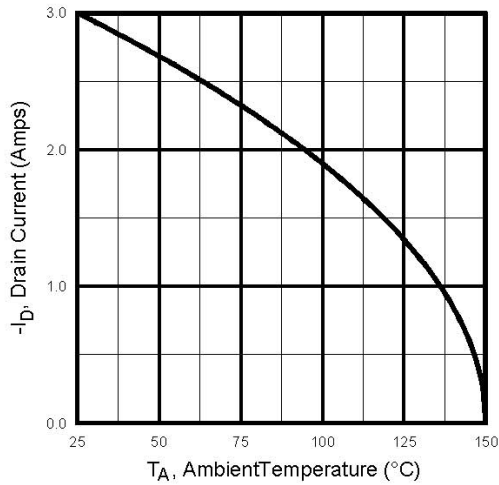
## P-Channel



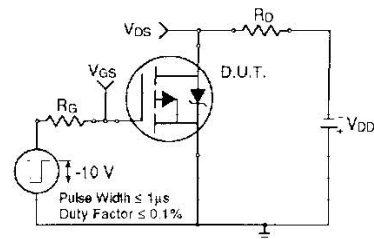
**Fig 18.** Typical Source-Drain Diode Forward Voltage



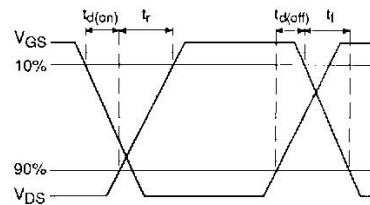
**Fig 19.** Maximum Safe Operating Area



**Fig 20.** Max. Drain Current Vs. Ambient Temp.

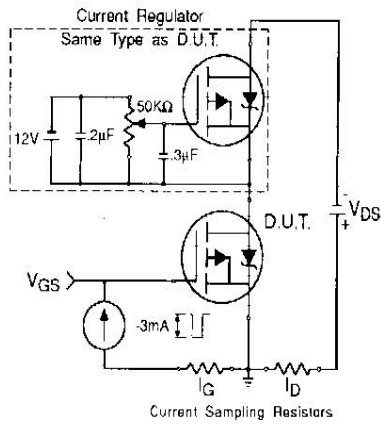


**Fig 21a.** Switching Time Test Circuit

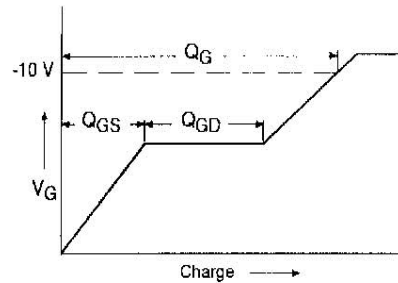


**Fig 21b.** Switching Time Waveforms

## P-Channel

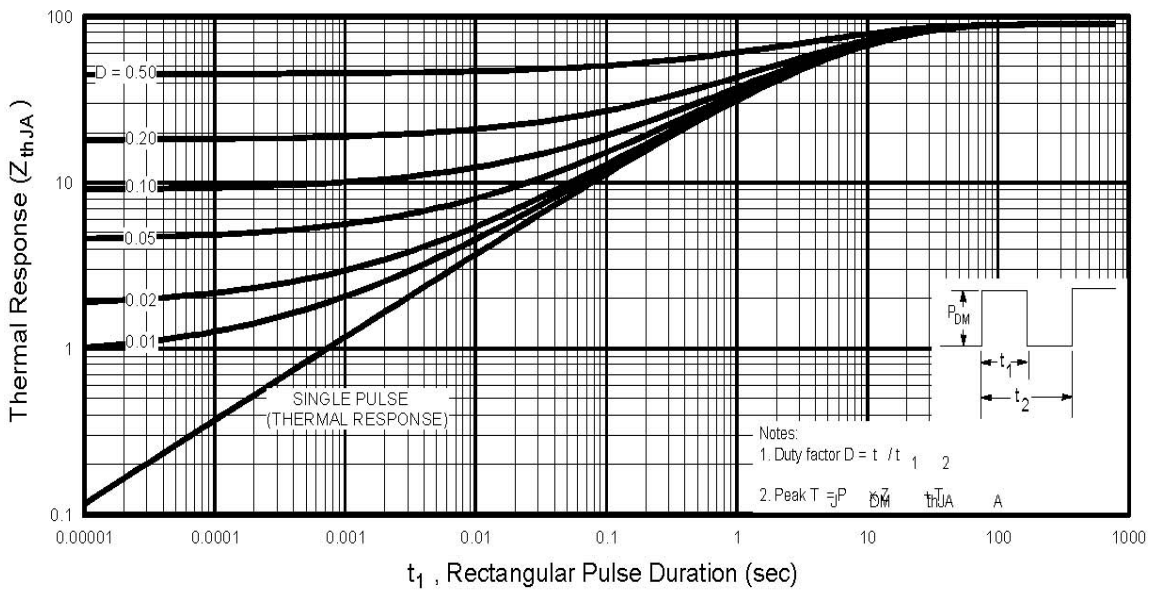


**Fig 22b.** Gate Charge Test Circuit



**Fig 22b.** Basic Gate Charge Waveform

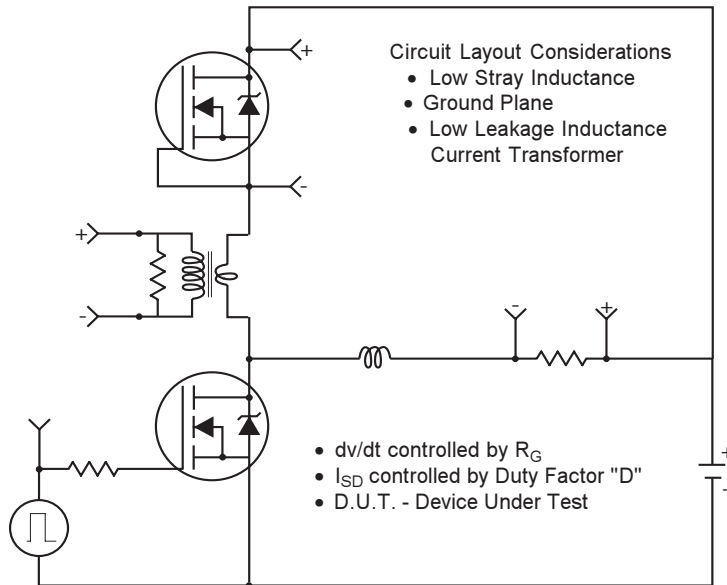
## N- and P-Channel



**Fig 23.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

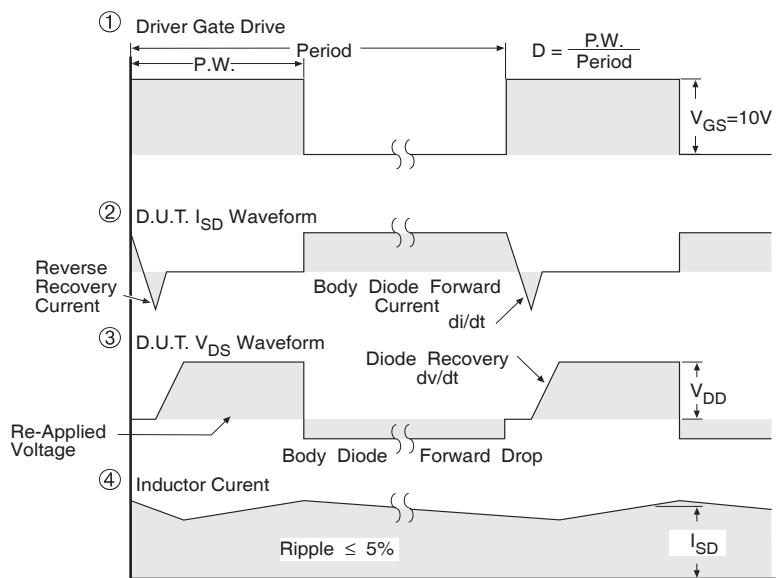


## Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity for P-Channel

\*\* Use P-Channel Driver for P-Channel Measurements



\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

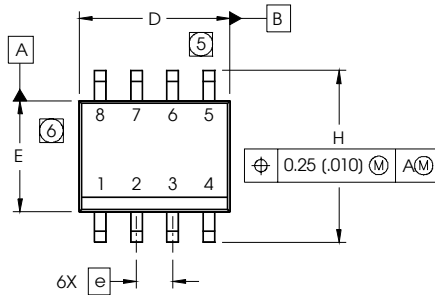
**Fig 24.** For N and P Channel HEXFETS

# IRF7309QPbF

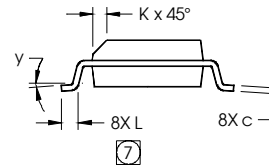
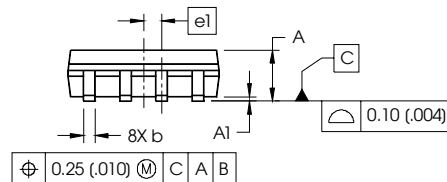
International  
**IR** Rectifier

## SO-8 Package Outline

Dimensions are shown in millimeters (inches)



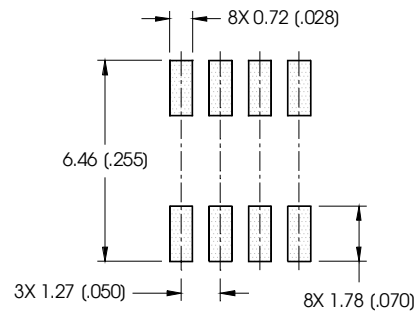
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050 BASIC		1.27 BASIC	
e1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



### NOTES:

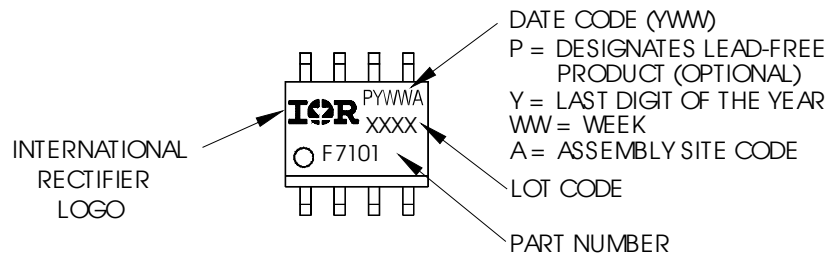
- DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- CONTROLLING DIMENSION: MILLIMETER
- DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- ⑤** DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
- ⑥** DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
- ⑦** DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

### FOOT PRINT



## SO-8 Part Marking

EXAMPLE: THIS IS AN IRF7101 (MOSFET)

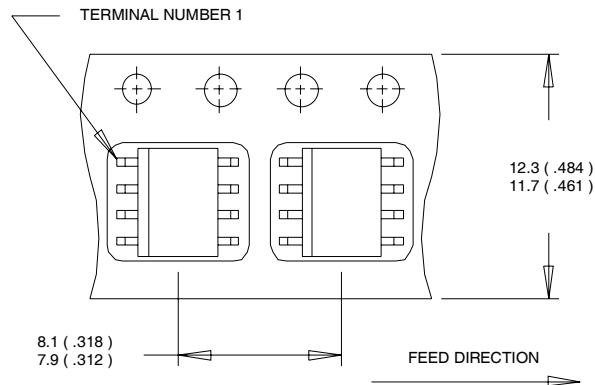


### Notes:

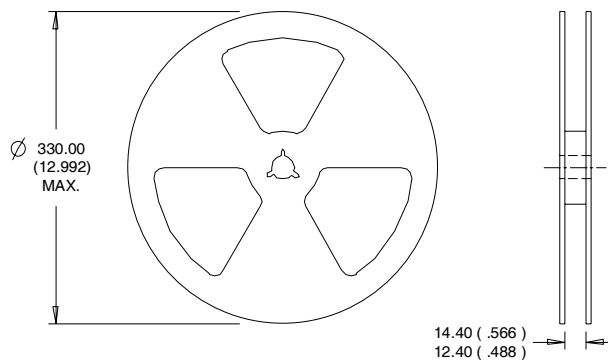
- For an Automotive Qualified version of this part please see <http://www.irf.com/product-info/auto/>
- For the most current drawing please refer to IR website at <http://www.irf.com/package/>

## SO-8 Tape and Reel

Dimensions are shown in millimeters (inches)



- NOTES:
1. CONTROLLING DIMENSION : MILLIMETER.
  2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
  3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



- NOTES :
1. CONTROLLING DIMENSION : MILLIMETER.
  2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice.  
 This product has been designed and qualified for the Industrial market.  
 Qualification Standards can be found on IR's Web site.